Application/Control No. 09/664,479 Applicant(s)/Patent Under Reexamination CHAPMAN ET AL. Examiner Tu X Nguyen Applicant(s)/Patent Under Reexamination CHAPMAN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,963,864	10-1999	O'Neil et al.	455/445
	В	US-			
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NON-PATENT DOCUMENTS

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